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# Microscopy AND Microanalysis



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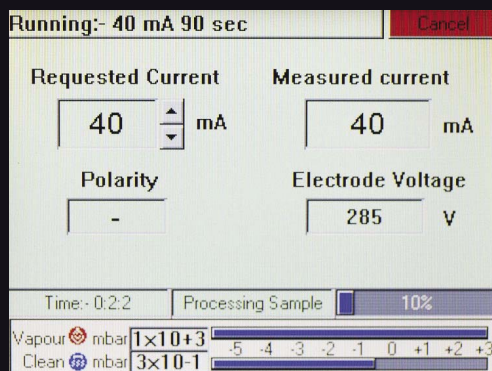
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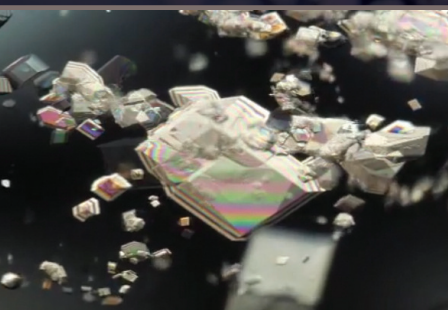
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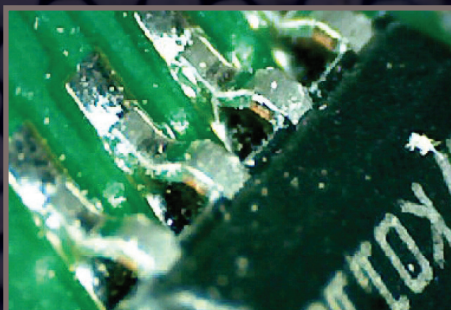
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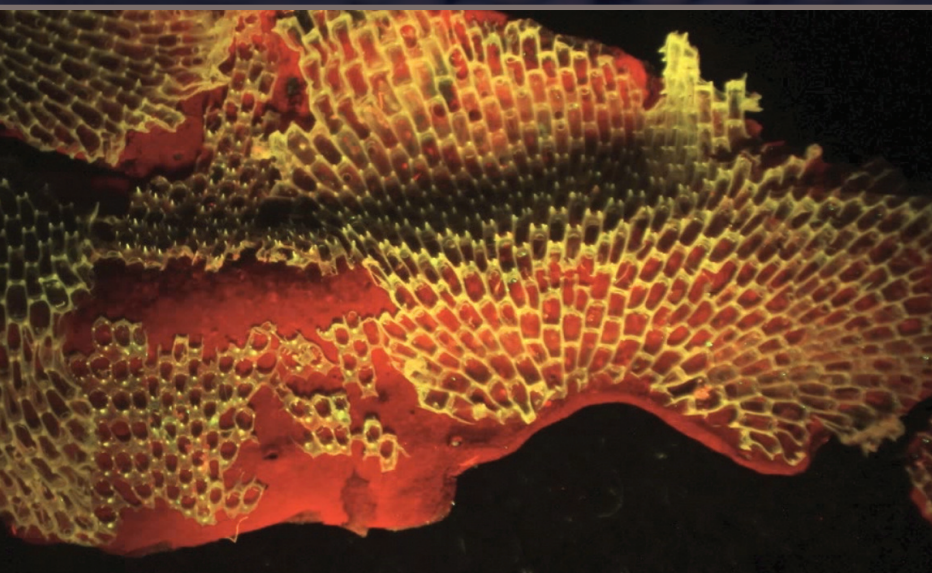
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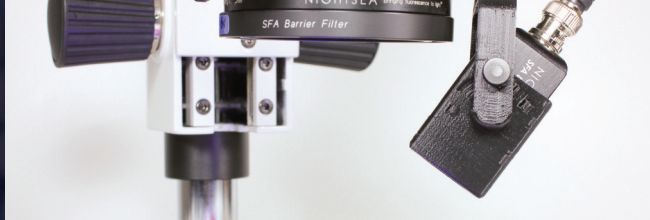
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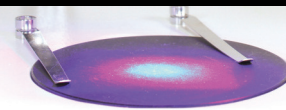
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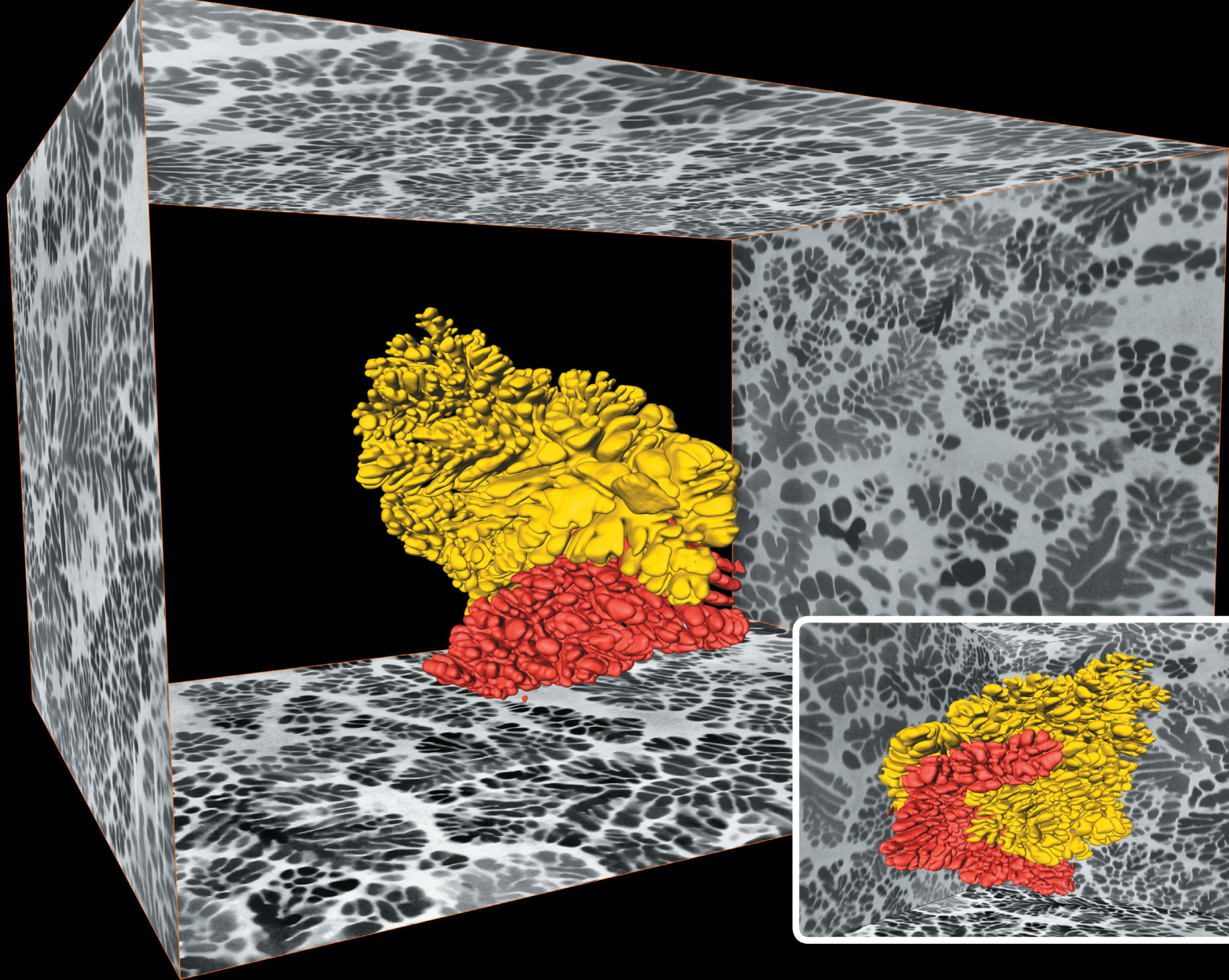
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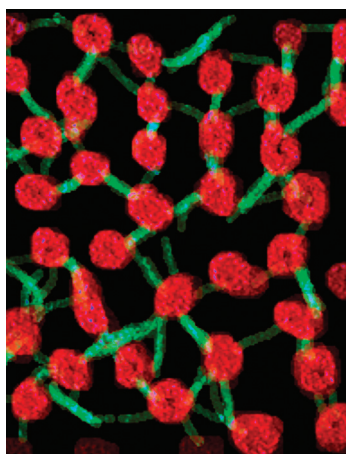
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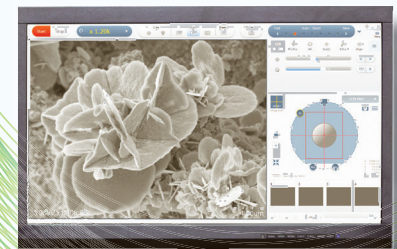
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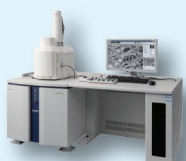
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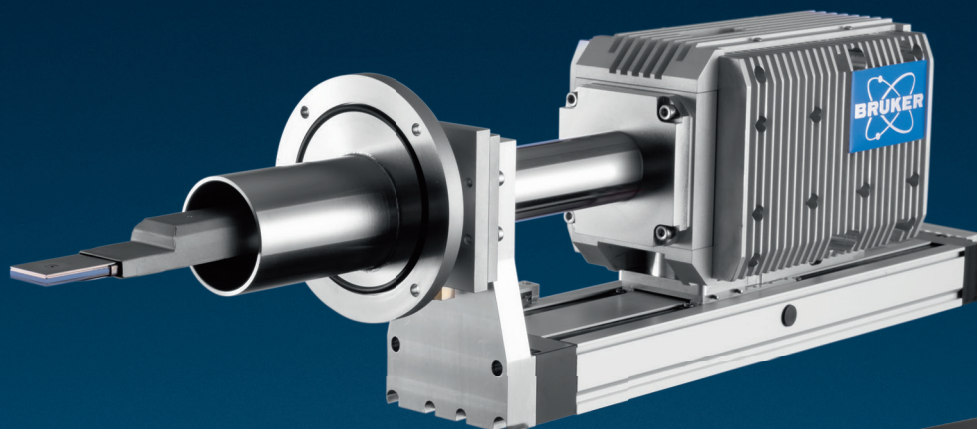
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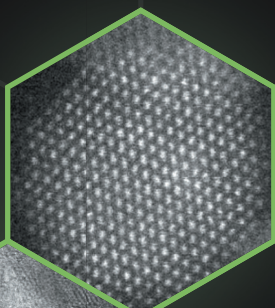
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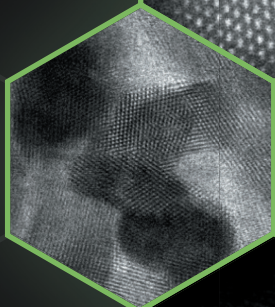
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Gold on  
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350 °C  
7.5 Torr N<sub>2</sub>

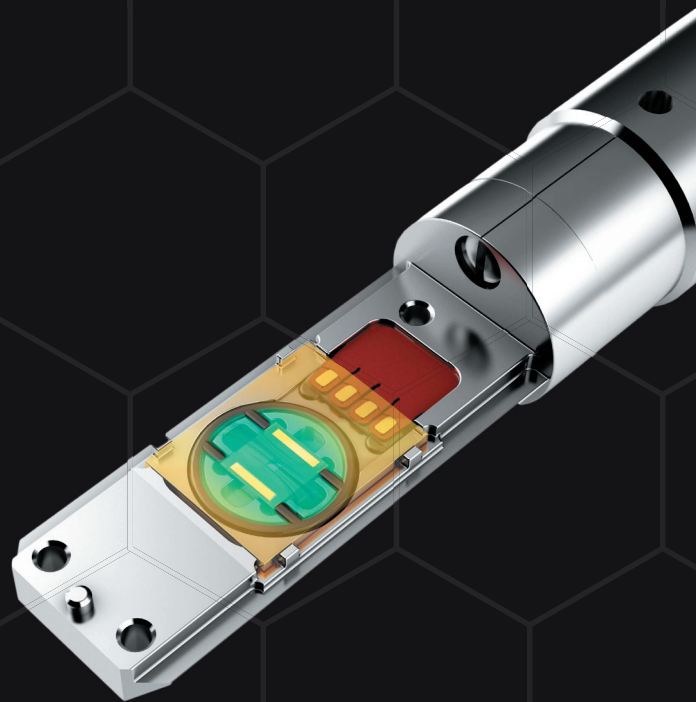
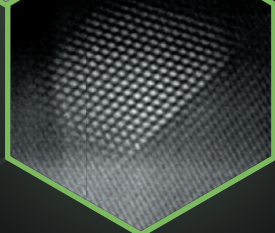


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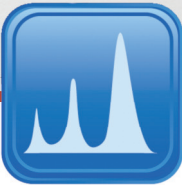
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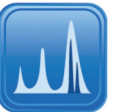
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